

Notice of References Cited

Application/Control No.

10/637,171

Applicant(s)/Patent Under
Reexamination
AMARU ET AL.

Examiner

Tan Dean D. Nguyen

Art Unit

3689

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,847,974	01-2005	Wachtel, David C.	707/101
	B	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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